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Attorney Docket No. 03506/LH

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Ryouichi YOKOYAMA et al
Serial No. : 10/650,059
Filed : August 27, 2003
For : STRESS MEASUREMENT METHOD
USING X-RAY DIFFRACTION
Art Unit : 2855
Examiner :

INFORMATION DISCLOSURE STATEMENT - I

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

Submitted herewith are five documents listed on the attached Form PTO/SB/08B. It is respectfully requested that the Examiner return an initialed copy of the attached Form PTO/SB/08B to confirm that the documents listed therein have all been considered and made of record.

Documents 1, 2 and 3 (as listed on the attached Form PTO/SB/08B) are identified and discussed in the "Description of the Related Art" section of the present specification appearing on pages 1-3 of the present specification. An English Abstract is supplied for Document 1. Documents 2 and 3 are in the English language.

Document 1 is also cited in a European Search Report enclosed with the Information Disclosure Statement -II filed concurrently herewith.

Document 2 is also referred to at page 14, lines 2-6 of the present specification.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on the date noted below.

Patricia O. Bryson
Patricia O. Bryson
Dated: June 17, 2004


In the event that this Paper is late filed, and the necessary petition for extension of time is not filed concurrently herewith, please consider this as a Petition for the requisite extension of time, and to the extent not tendered by check attached hereto, authorization to charge the extension fee, or any other fee required in connection with this Paper, to Account No. 06-1378.

The publication edited by Kohra (Document 4 on the attached Form PTO/SB/08B) is discussed on page 10 of the present specification, and is identified at page 10, lines 15-19 of the present specification. A partial English translation of Document 4 is attached to the document.

The Sakurai document (Document 5 on the attached Form PTO/SB/08B) is identified and discussed near the bottom of page 14 of the present specification. A partial English translation of Document 5 is attached to the document.

It is respectfully requested that the Examiner consider the documents submitted herewith and make them of record.

Respectfully submitted,



Leonard Holtz
Reg. No. 22,974

Dated: June 17, 2004

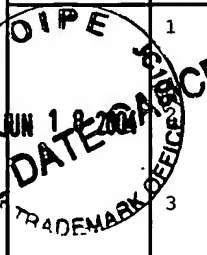
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PTO/SB/08B (08-00)

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Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT			Application Number		10/650,059	
			Filing Date		August 27, 2003	
			First Named Inventor		Ryouichi YOKOYAMA et al	
			Group Art Unit		2855	
			Examiner Name			
Sheet	1	of	1	Attorney Docket Number		03506/LH
OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published				T ²
	1	K. TANAKA, K. ISHIHARA and K. INOUE: "A METHOD OF X-RAY STRESS MANAGEMENT FOR CUBIC POLYCRYSTALS WITH FIBER TEXTURE", J. Soc. Mat. Sci., Japan, Vol. 45, No. 8, pages 945-950, August, 1996.				
		K. TANAKA, Y. AKINIWA, T. ITO and K. INOUE: "ELASTIC CONSTANTS AND X-RAY STRESS MEASUREMENT OF CUBIC THIN FILMS WITH FIBER TEXTURE", JSME International Journal, Series A, Vol. 42, No. 2, pages 224-234, 1998.				
	3	K. TANAKA and Y. AKINIWA: "X-RAY STRESS MANAGEMENT OF HEXAGONAL POLYCRYSTALS WITH [001] FIBER TEXTURE", JSME International Journal, Series A, Vol. 41, No. 2, pages 287-289, 1998.				
	4	Jikkenbutsurigaku kouza 20, X-sen kaisetsu (Experimental physics course 20, x-ray diffraction), edited by K. Kohra, KYORITSU SHUPPAN CO., LTD., 1998, pages 571-575, "16.2 x-sen ouryokusokuteino genri (Principle of X-ray stress measurement)".				
	5	X-sen kesshoukaisekino tebiki, Ouyoubutsurigaku sensho (Guide to X-ray Crystal Analysis, Applied Physics Sampler), T. Sakurai, Shokabou, 1983, page 53.				
Examiner Signature				Date Considered		

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² Place a check here if English translation is attached.

DATE MAILED: June 17, 2004